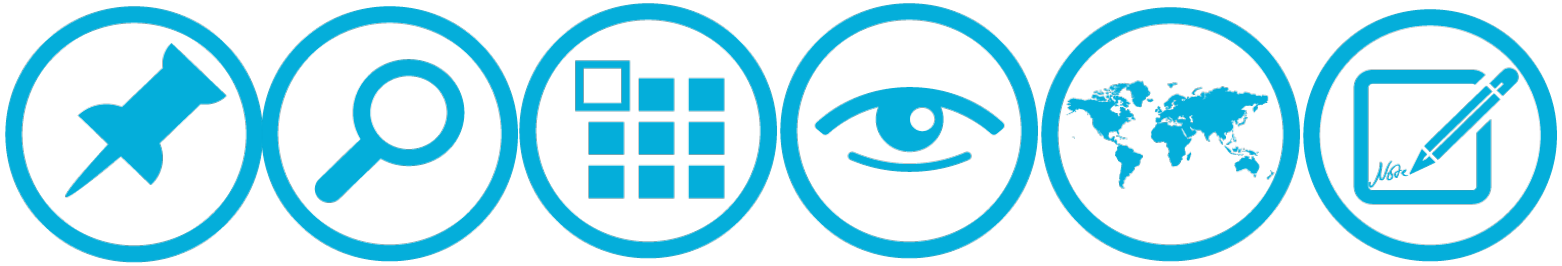
The Influence of Space Radiation on the Relative Permittivity of Dielectrics



Siyu Song
Institute of Space Science and Applied Technology, Peking University

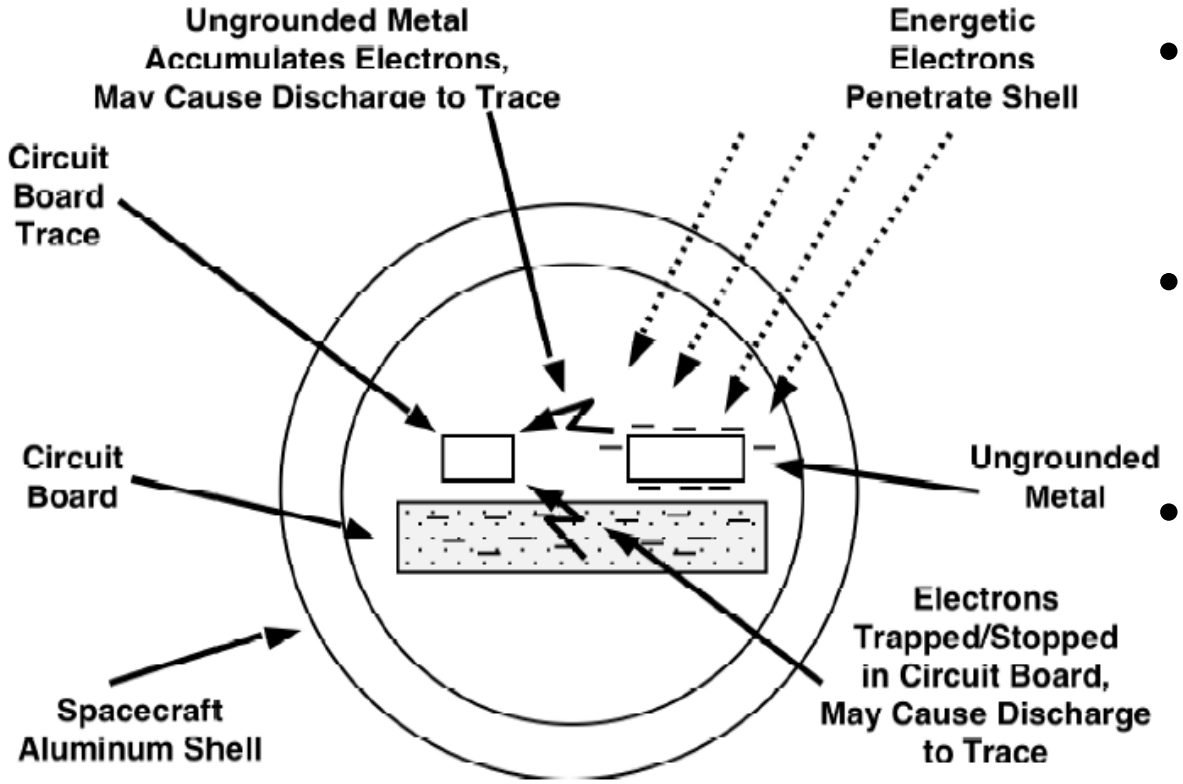
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1 Introduction



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Introduction



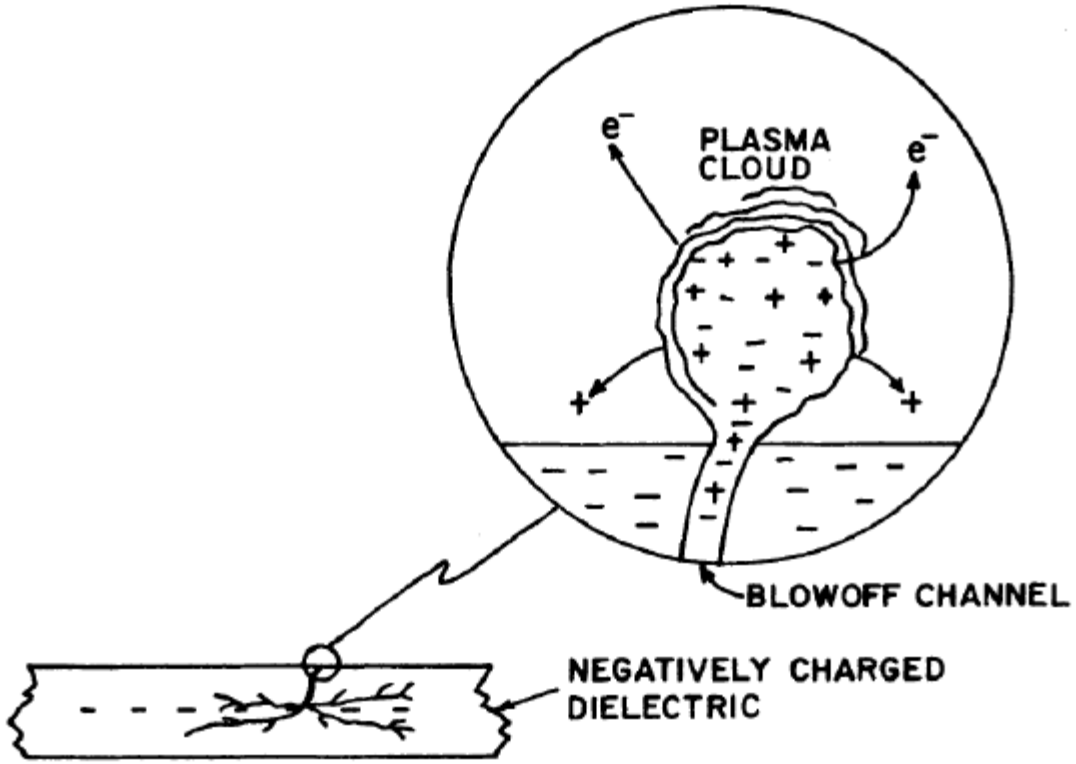
[NASA-HDBK-4002A]

- Energetic electrons will penetrate into interior portions of a spacecraft.
- Electrons may be stopped in dielectrics or on ungrounded conductors.
- If too many electrons accumulate, the resultant high electric fields may cause an ESD to a nearby victim circuit.

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Introduction

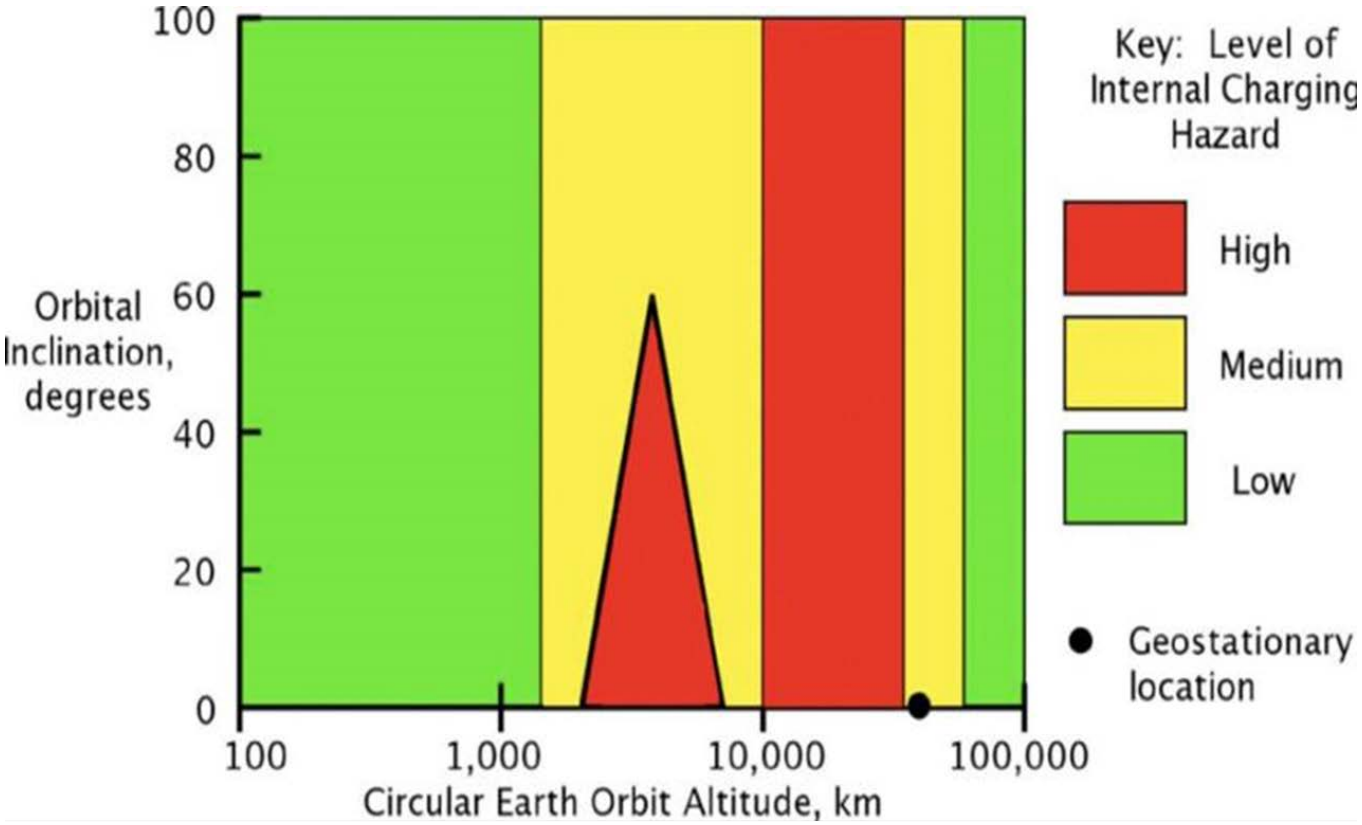
- Discharge creates a local plasma.
- Current increases on nearby conductors that are grounded.
- Voltage of the dielectrics decreases.
- Discharge pulses can be detected.



[A.R.Frederickson,1983]

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Introduction

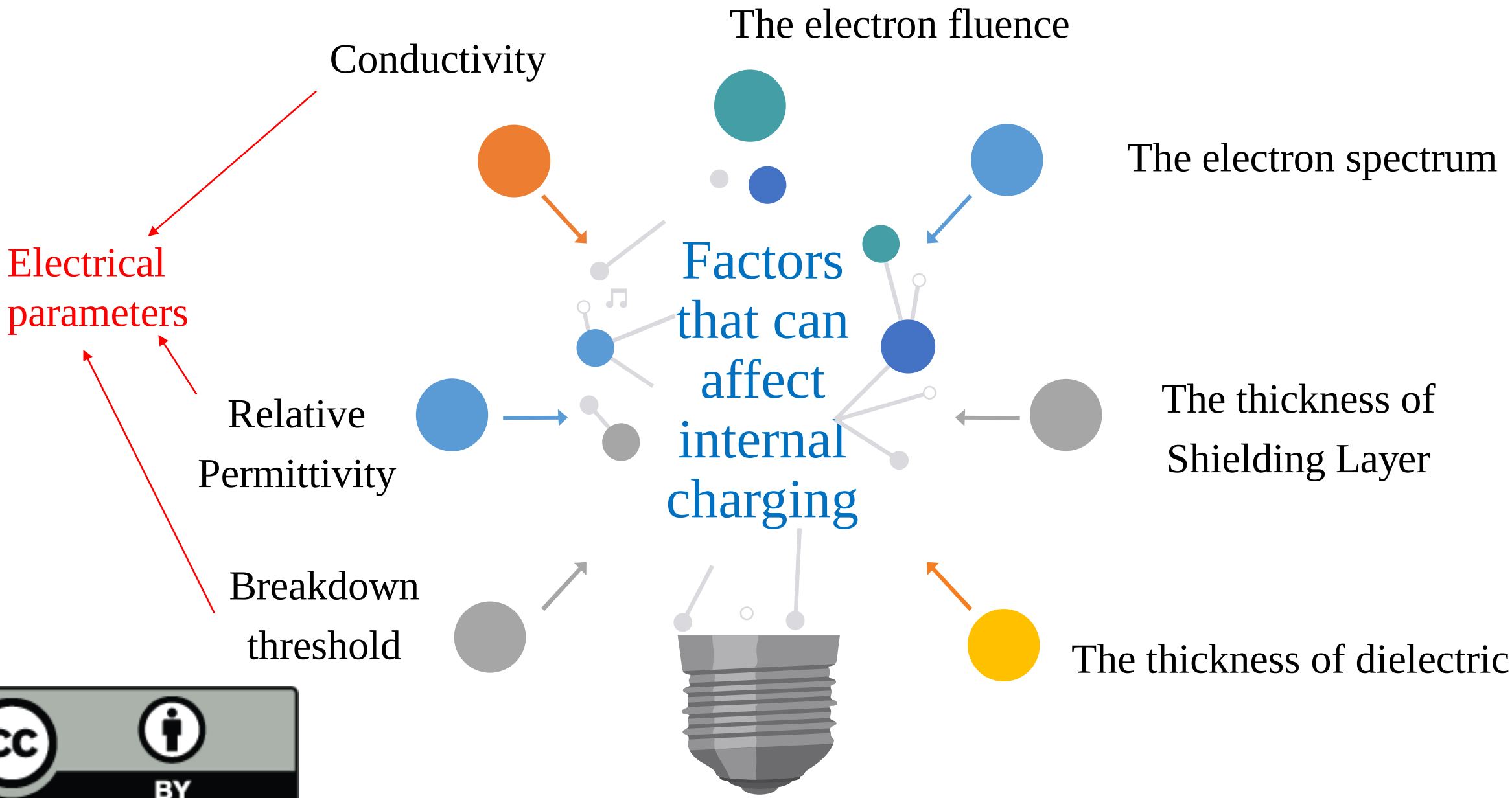


[NASA-HDBK-4002A]

- Earth's internal charging threat regions is estimated assuming averages electron fluence over several orbits.
- Satellites on MEO and GEO orbits are at high risk of internal charging threat.

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Introduction



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1 Introduction

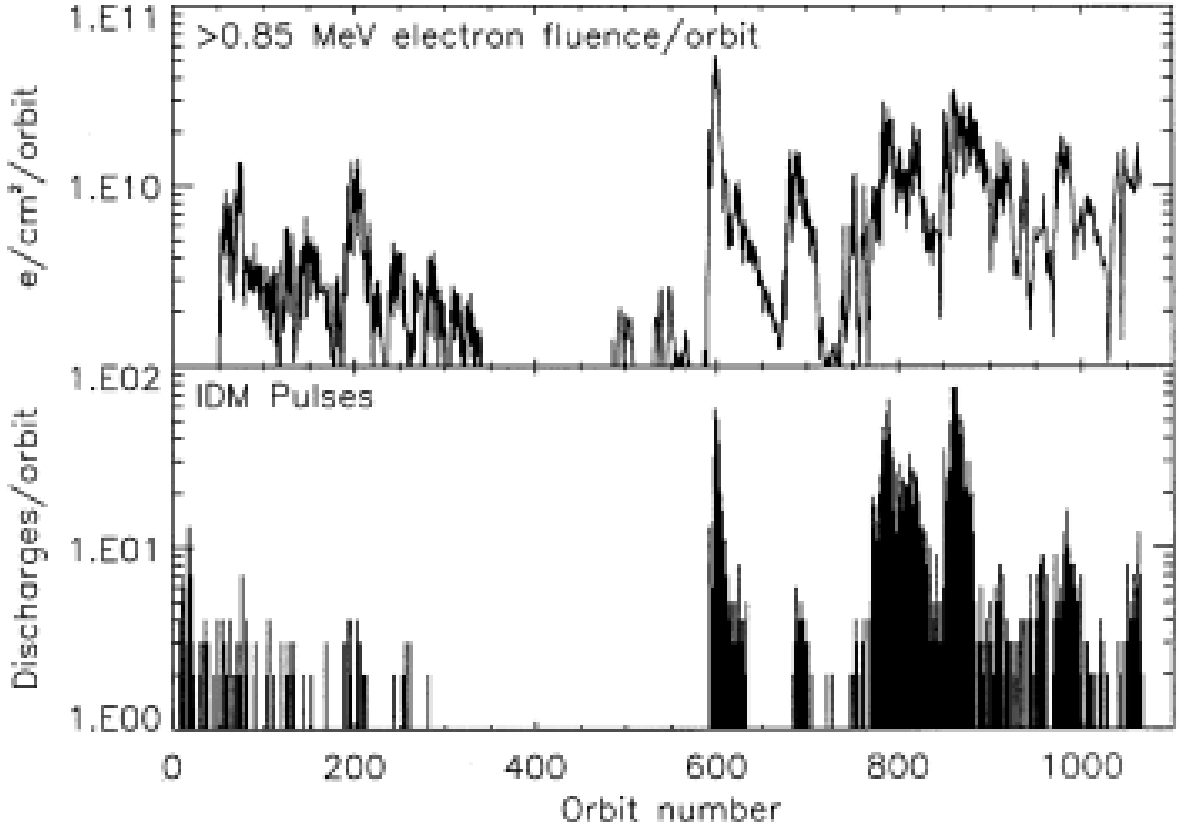
2 Phenomena

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Phenomena

- CRRES was launched on 1990, carrying a electron detector, Internal Discharge Monitor(IDM), 16 different dielectric samples.

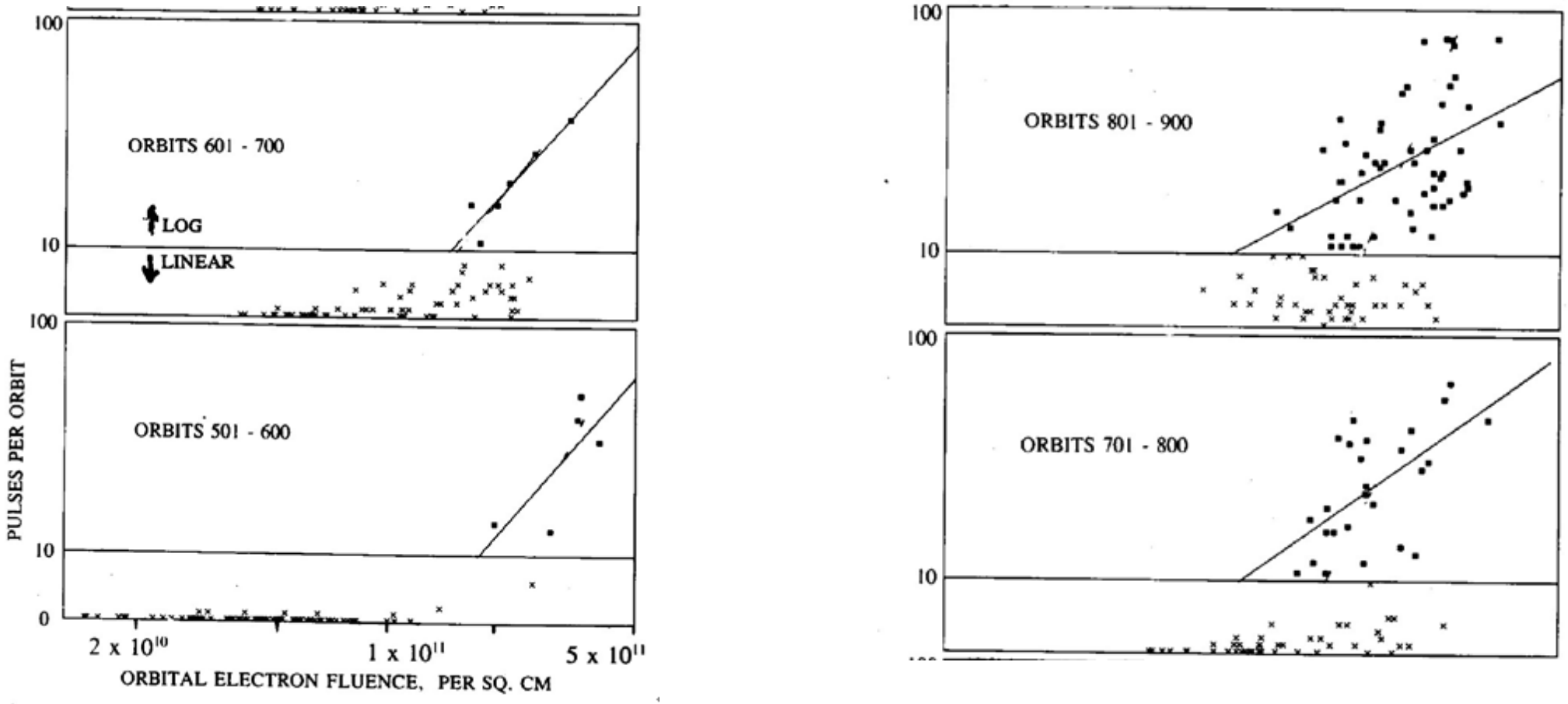
- The electron fluence and discharge pulses of each sample per orbit is collected.



[A.R.Frederickson, 1992]

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Phenomena



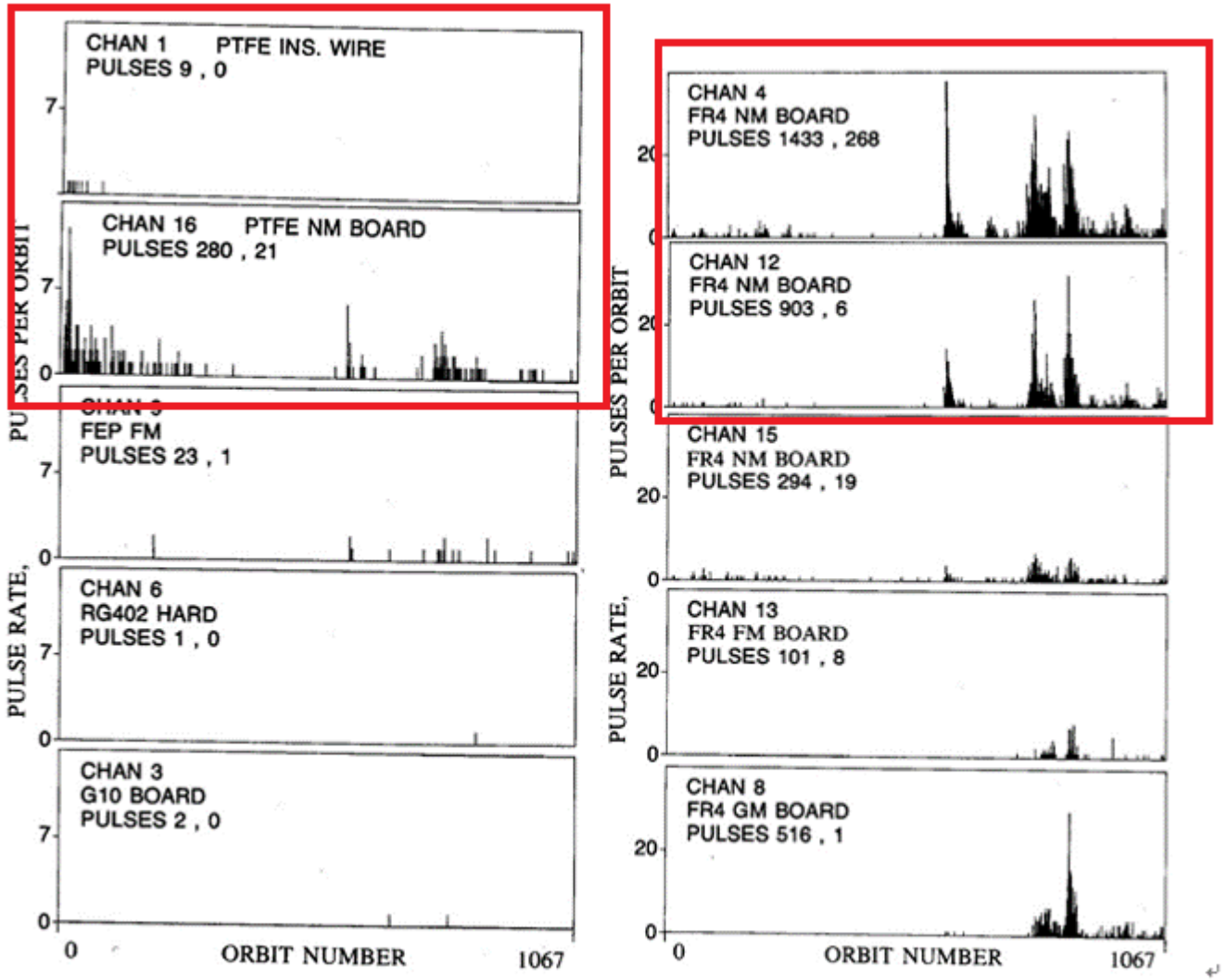
[A.R.Frederickson, 1992]

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- No clear relationship between pulses and orbital electron fluence.

Phenomena

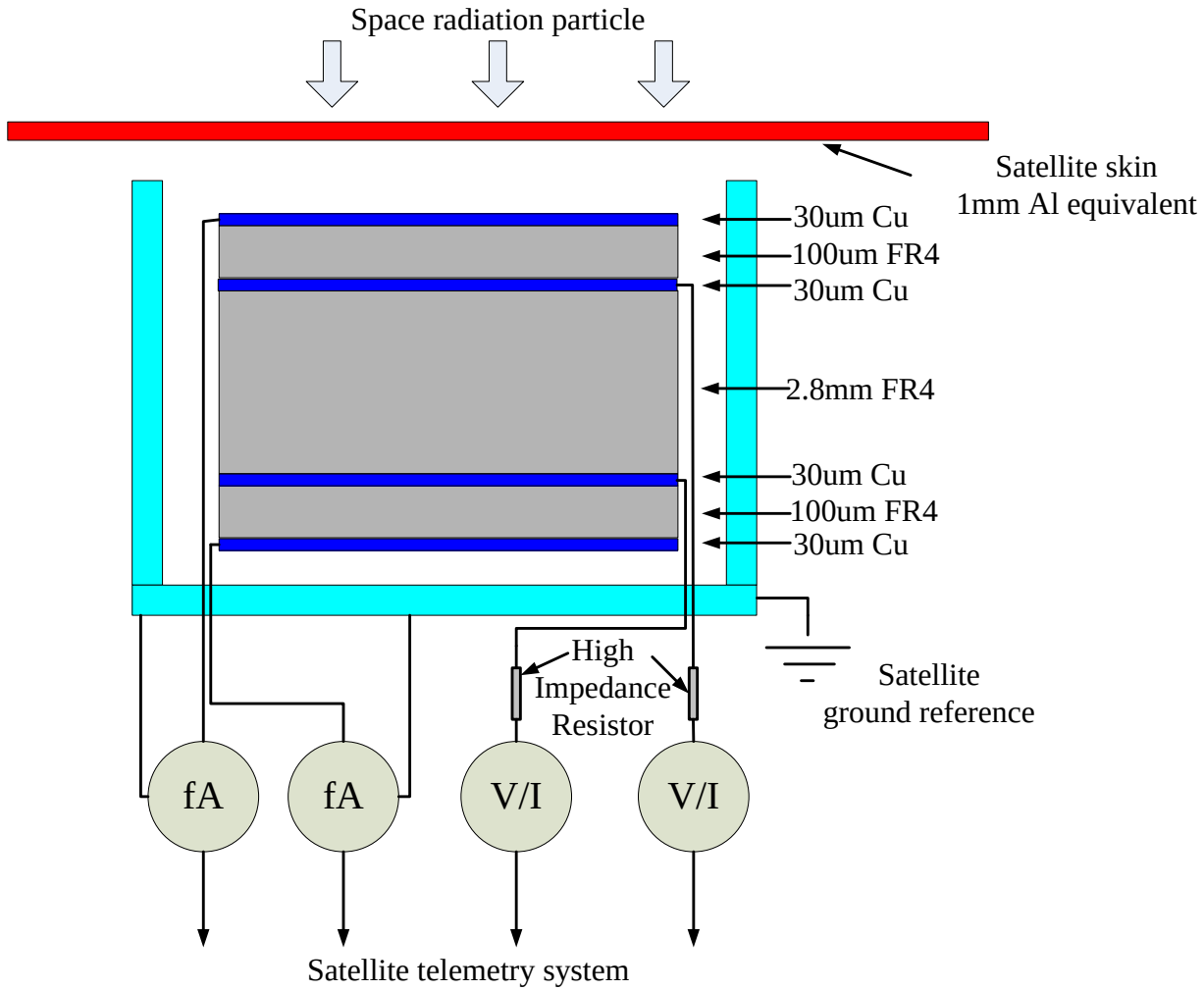
- The discharge frequency of different samples changed with the increase of time.
- The accumulated electron radiation dose may affect properties of the dielectric samples.



[A.R.Frederickson, 1992]

Phenomena

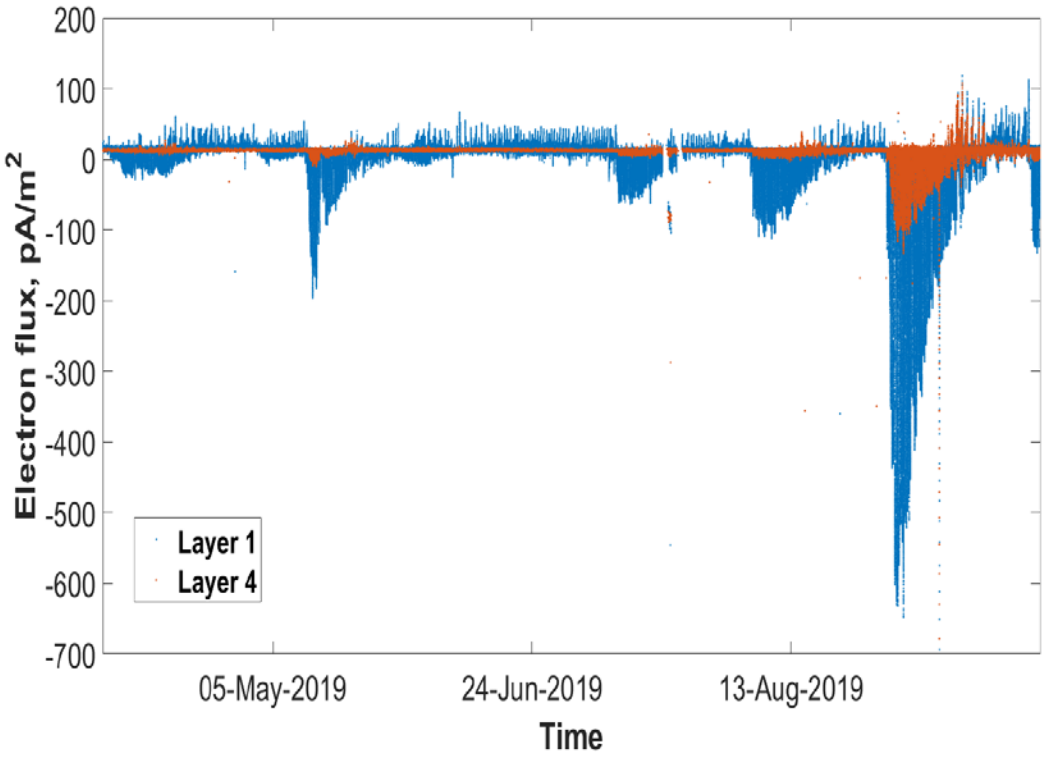
- The Deep Dielectric Charging Effects Monitor(DDCEM) carried by BD3M17 satellite was launched on Nov 1st, 2018.
- DDCEM can monitor leakage current and internal potential of FR4 samples.

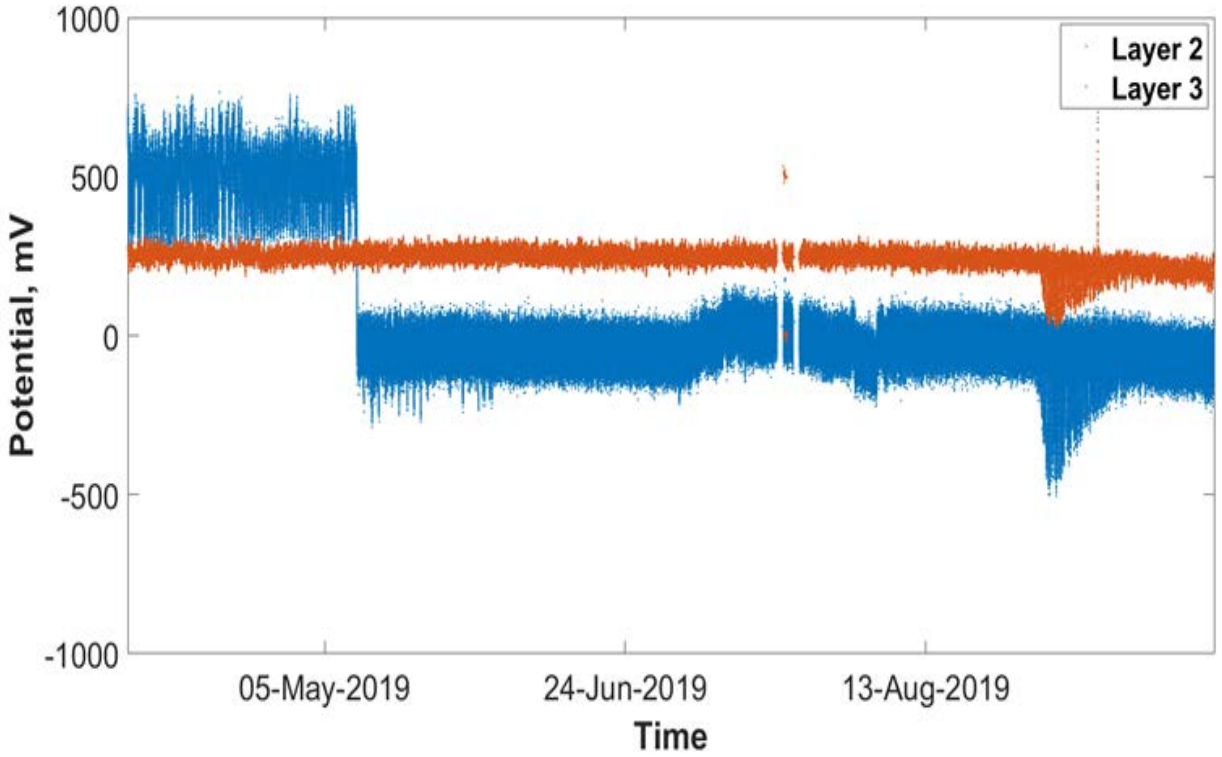


[Yu Xiangqian, 2019]

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Phenomena





[Yu Xiangqian, 2019]

- Internal potential decreased with the increase of time.
- Dielectric properties may have changed due to the electron radiation dose.

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1 Introduction

2 Phenomena

3 Geant4-RIC

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Geant4-RIC

$$\varepsilon \frac{\partial E(x,t)}{\partial x} = \rho_{-}(x,t) + \rho_{t-}(x,t),$$

Poisson Equations

$$\mu_{-}\rho_{-}(x,t)E(x,t) + \sigma(x)E(x,t) + J(x) + \varepsilon \frac{\partial E(x,t)}{\partial t} = J_0(x,t),$$

The equation of continuity

$$\frac{\partial \rho_{t-}(x,t)}{\partial t} = \frac{\rho_{-}(x,t)}{\tau_{-}}\left(1 - \frac{\rho_{t-}(x,t)}{\rho_m}\right),$$

The rate equation for deep trapping of negative charges

$$V(x,t) = -\int_0^x E(x,t)\mathrm{d}x.$$

The equation of voltage

$$\sigma = \sigma_d + \sigma_r = \sigma_d + k\dot{D}^{\Delta}.$$

$$\frac{\sigma}{\sigma_0} = \frac{2 + \cosh\left(\beta_F E^{1/2} / 2k_B T\right)}{3},$$

The equation of conductivity containing RIC and E

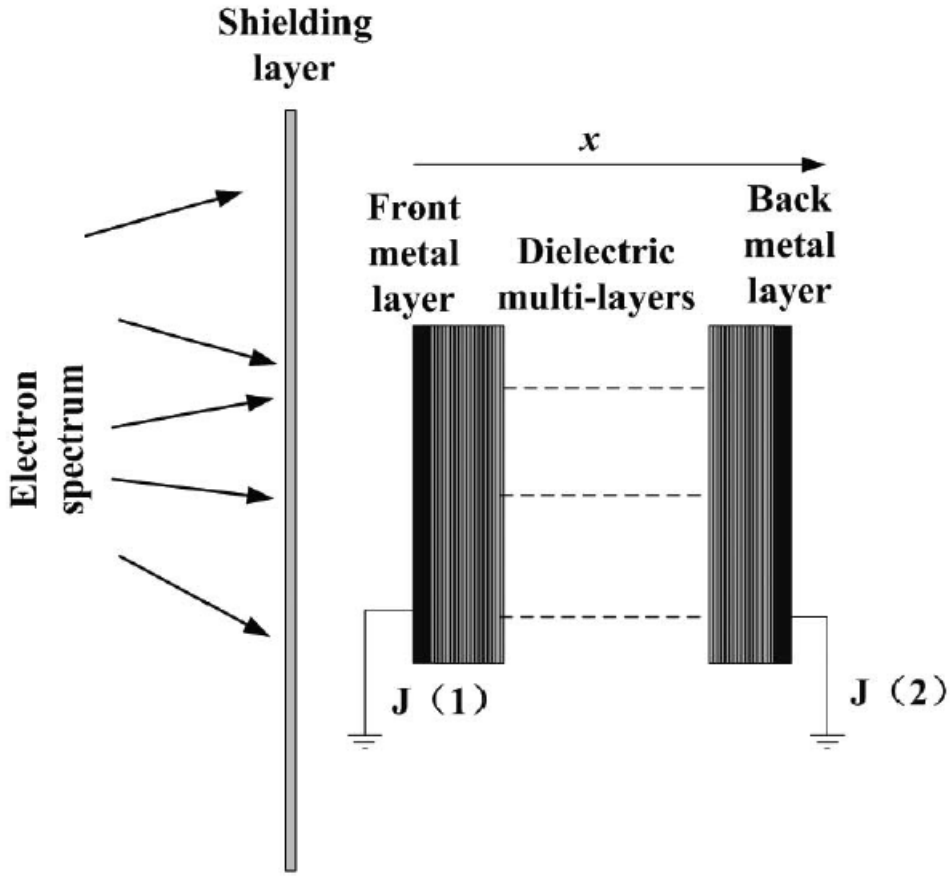
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Geant4-RIC

$$\dot{D} = 1.6 \times 10^{-11} \cdot \frac{E_d}{T_s \rho A_m \Delta x},$$

$$J = -\frac{Qe}{T_s A_m},$$

- The radiation dose rate and current density are calculated by the Monte Carlo method of Geant4



[Yu Xiangqian, 2016]

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- If E(x,0)=0, V(x,0)=0 j is constant

The electric field of dielectric during the charge process is:

$$E = \frac{j}{\sigma}\left[1 - \exp\left(-\frac{\sigma t}{\varepsilon}\right)\right]$$

The electric field of dielectric during the discharge process is:

$$E = E_0 \exp\left(-\frac{\sigma t}{\varepsilon}\right)$$

The time constant of charge and discharge is：

$$\tau = \frac{\varepsilon}{\sigma}$$

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1 Introduction

2 Phenomena

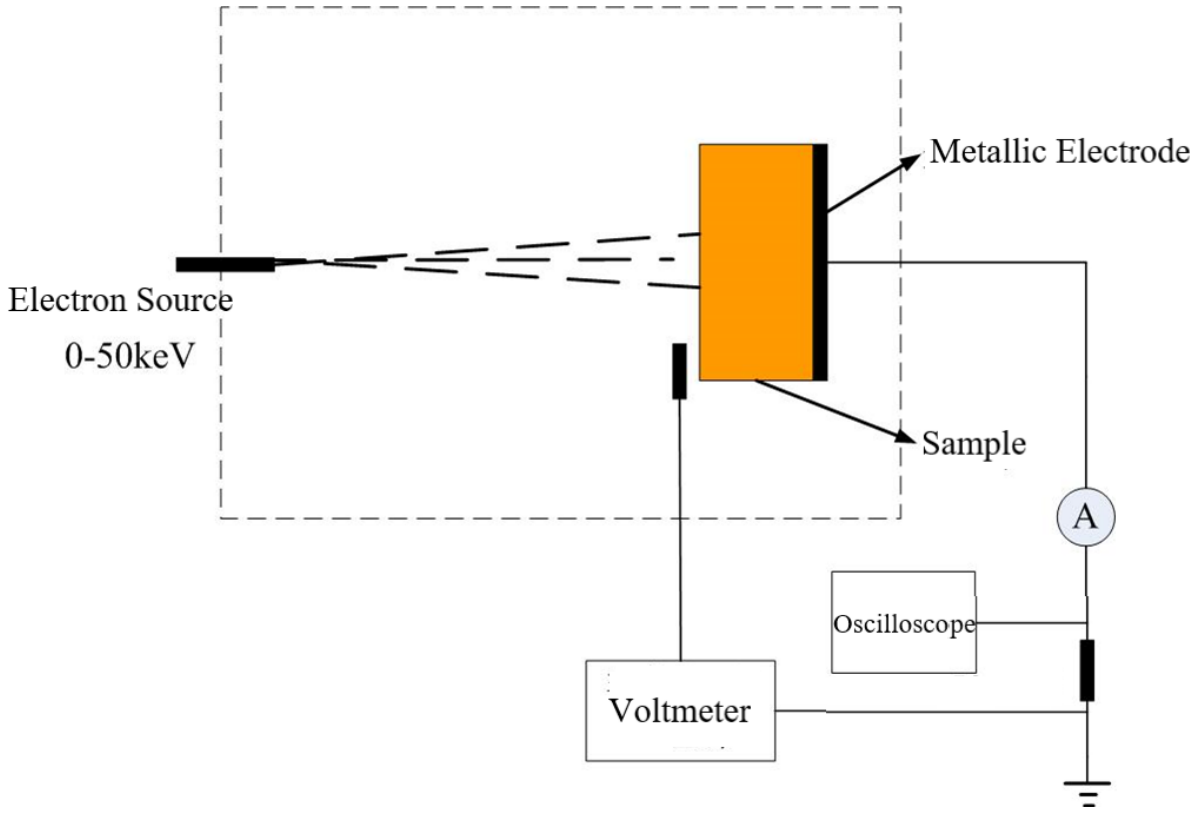
3 Geant4-RIC

4 Ground Experiment

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Ground Experiment

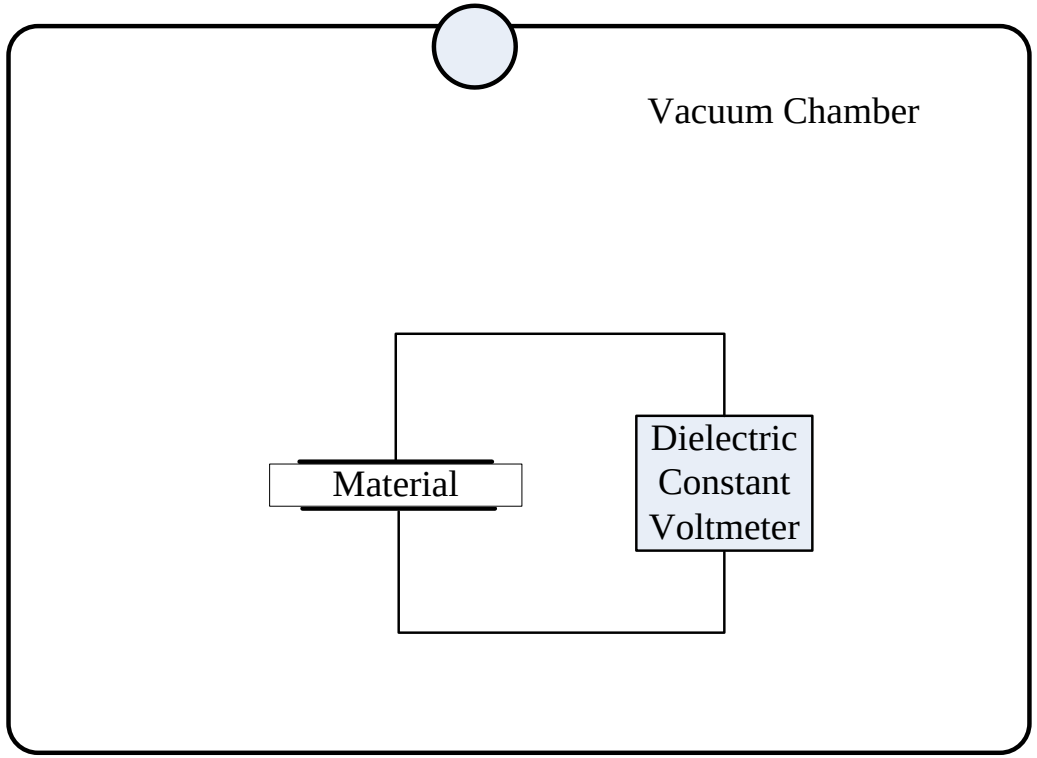
- Energy： 30KeV
- Current： 1600pA/cm^2
- Radiation dose:10M, 25M, 30Mrad
- Sample： Polyimide
- Sample Thickness: 50um
- Temperature： 300K



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Ground Experiment

- Three same samples was exposed to different radiation dose.
- The relative permittivity of the sample was measured after the charge and discharge process finished.



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1 Introduction

2 Phenomena

3 Geant4-RIC

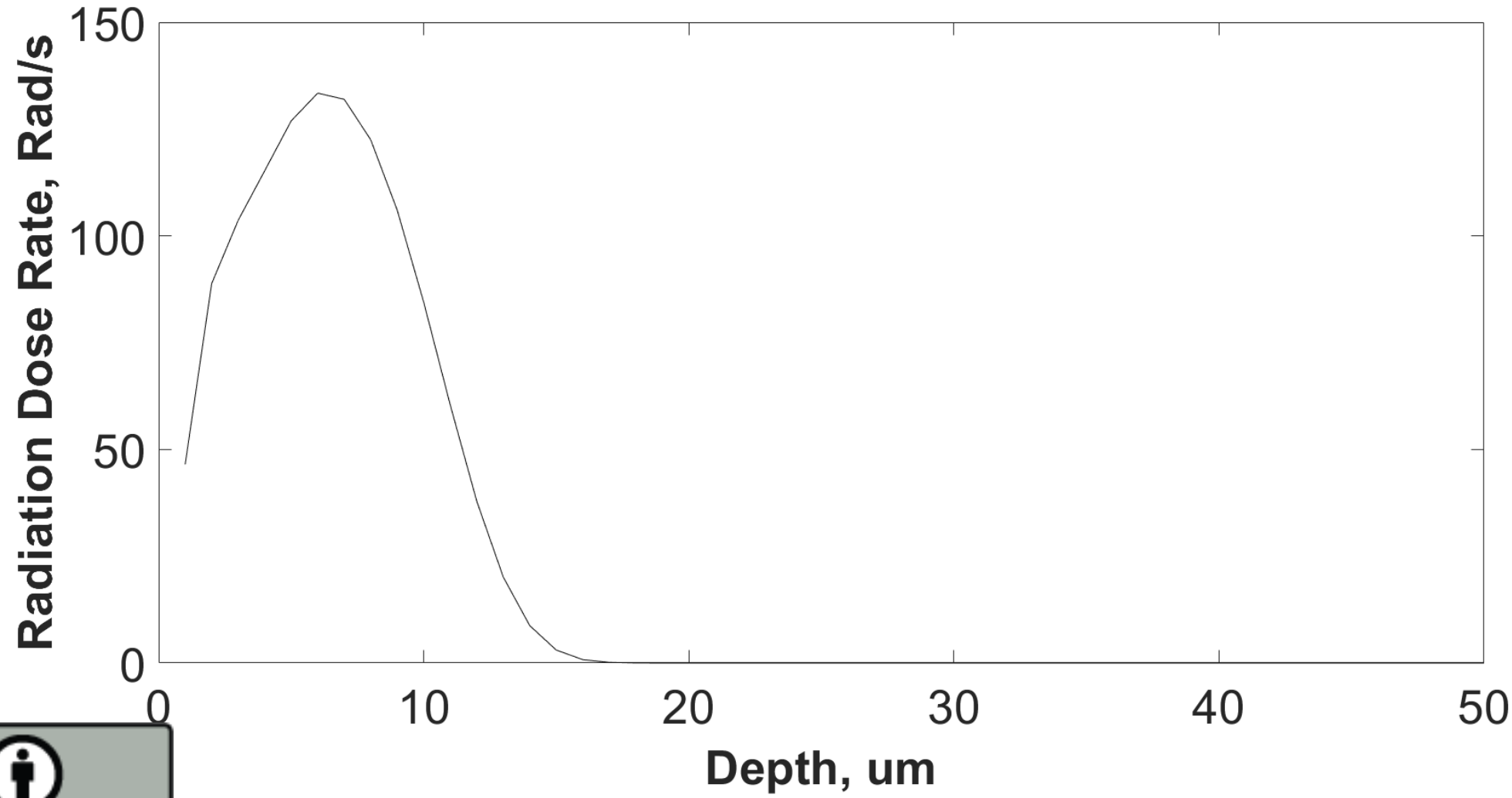
4 Ground Experiment

5 Results

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Results

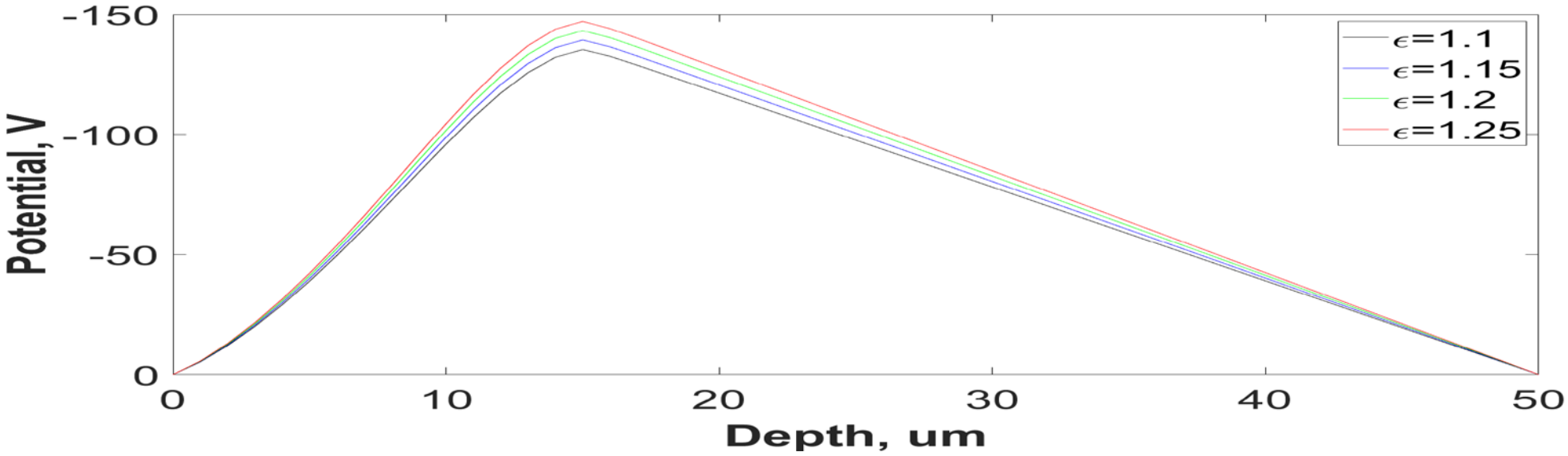
The result of the Geant4 – RIC simulation

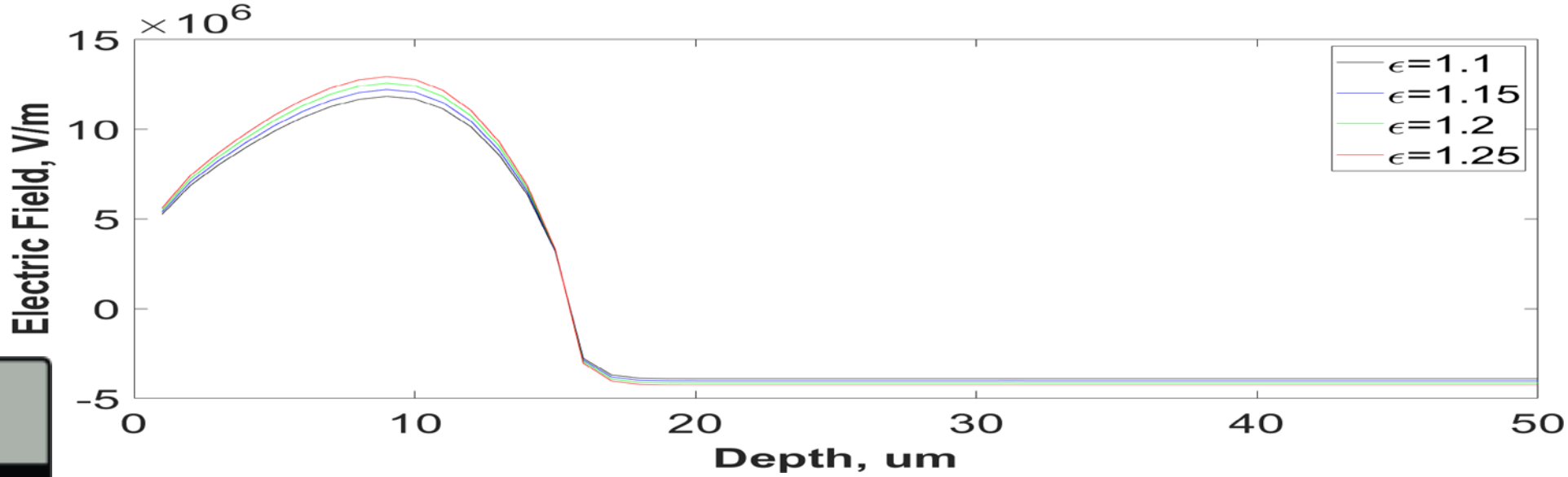


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Results

The charge process

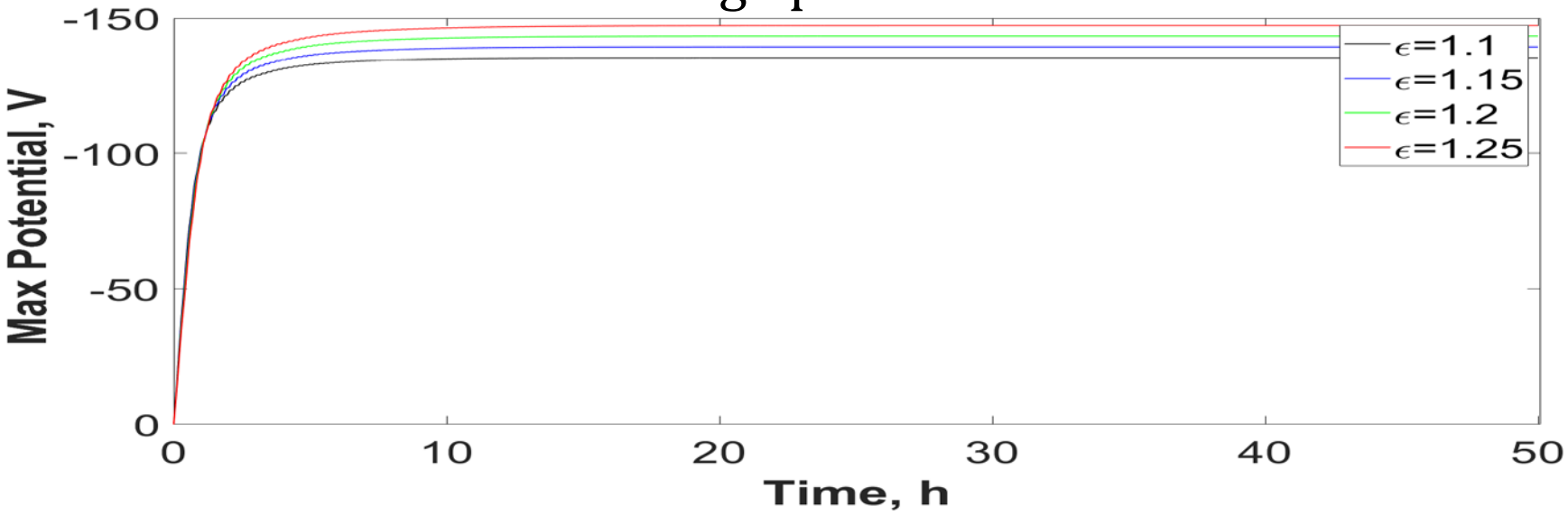


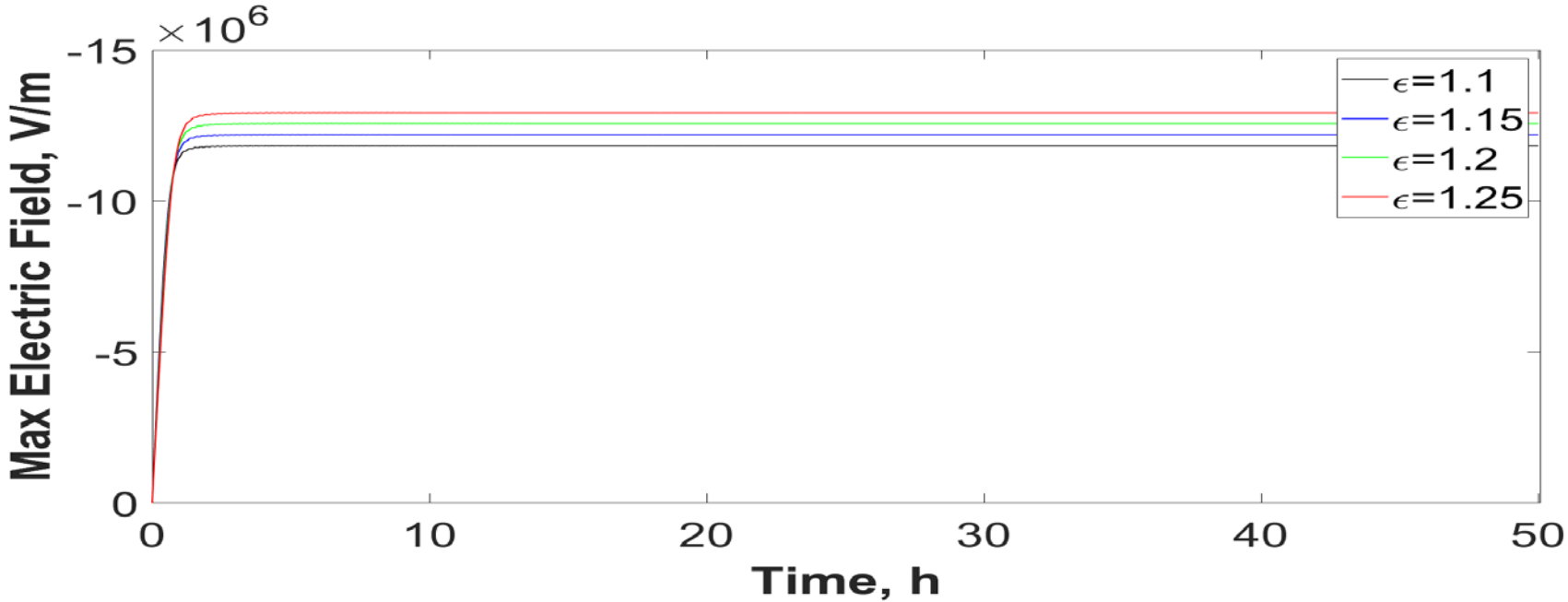


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Results

The charge process

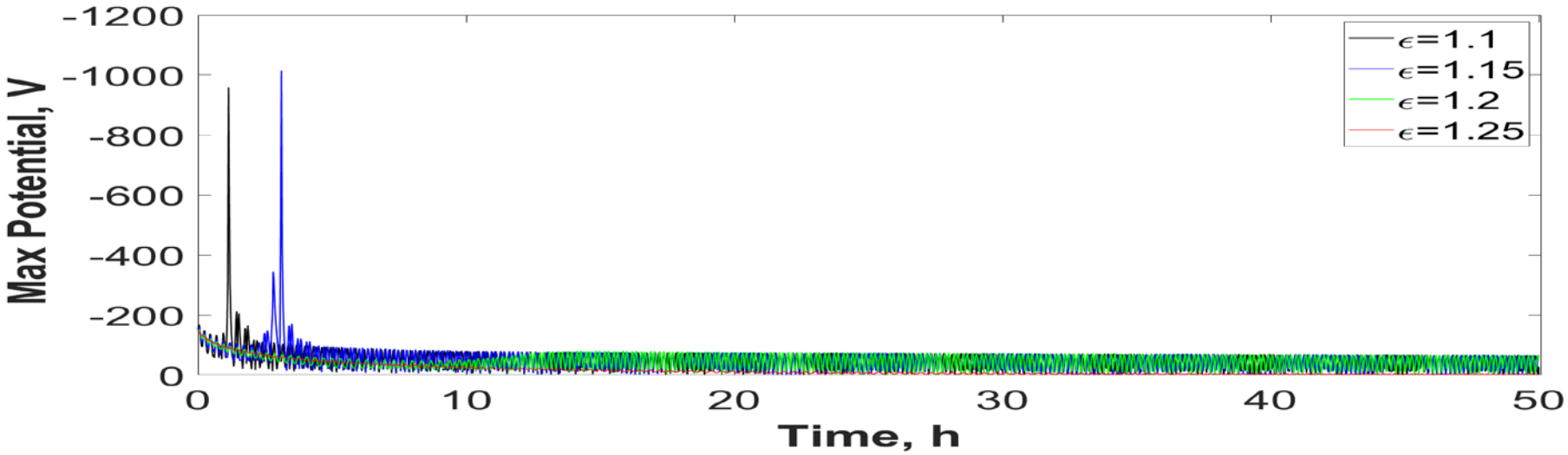


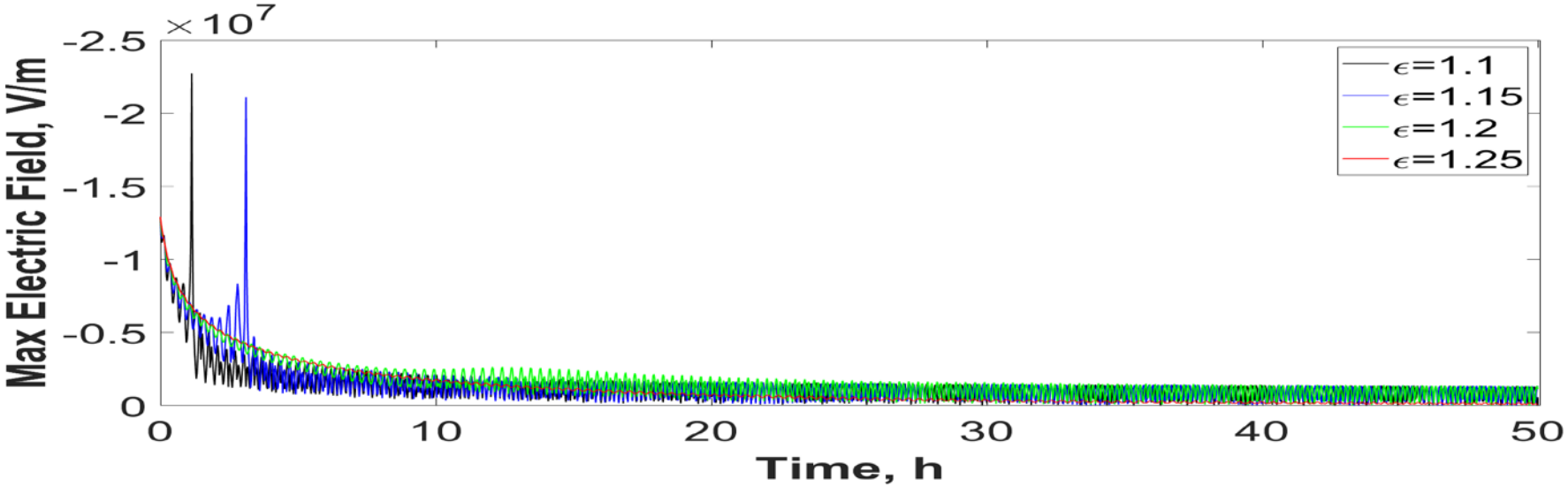


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Results

The discharge process

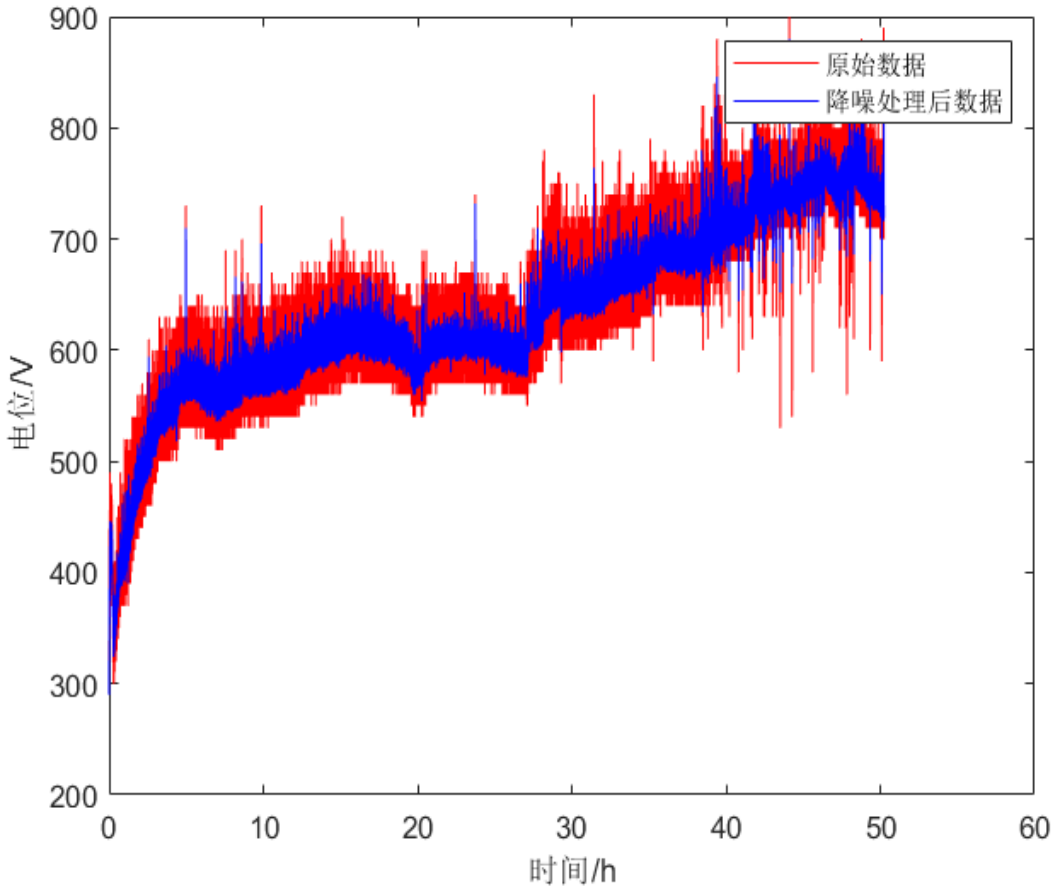




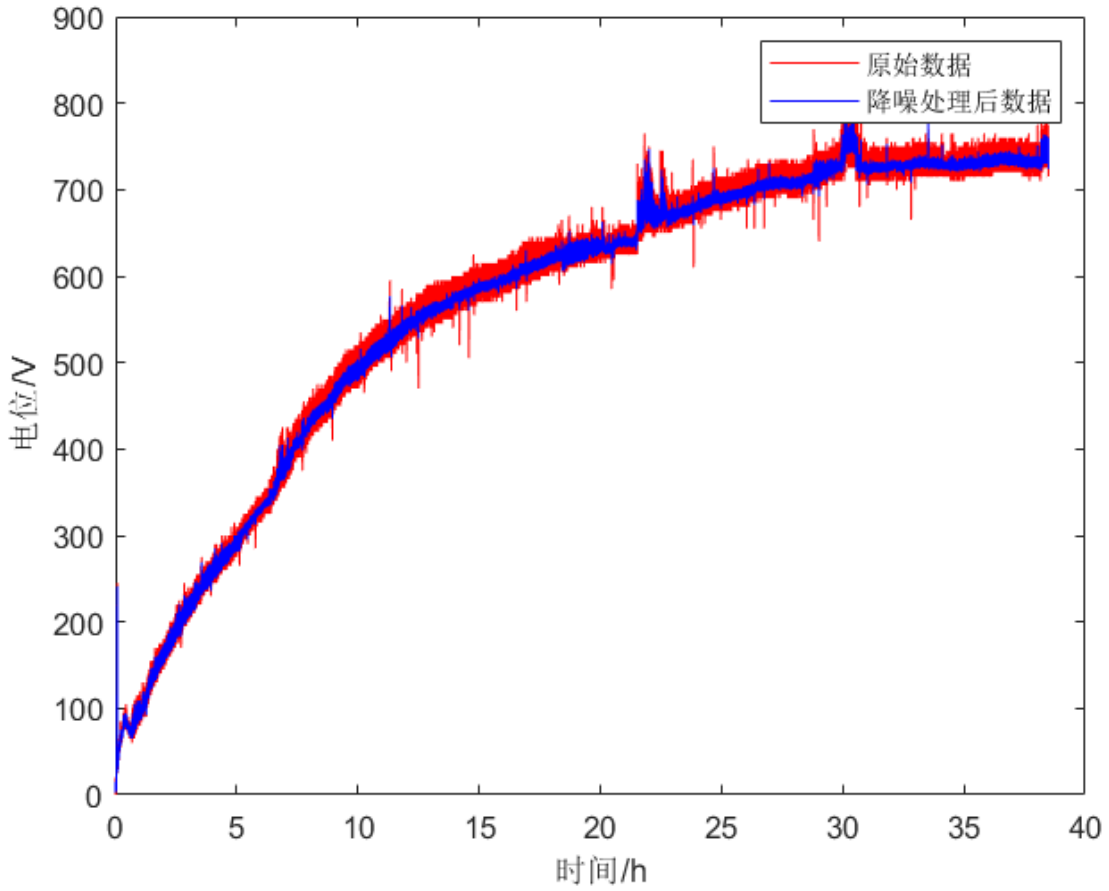
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Results

The result of the ground experiment



10Mrad irradiation

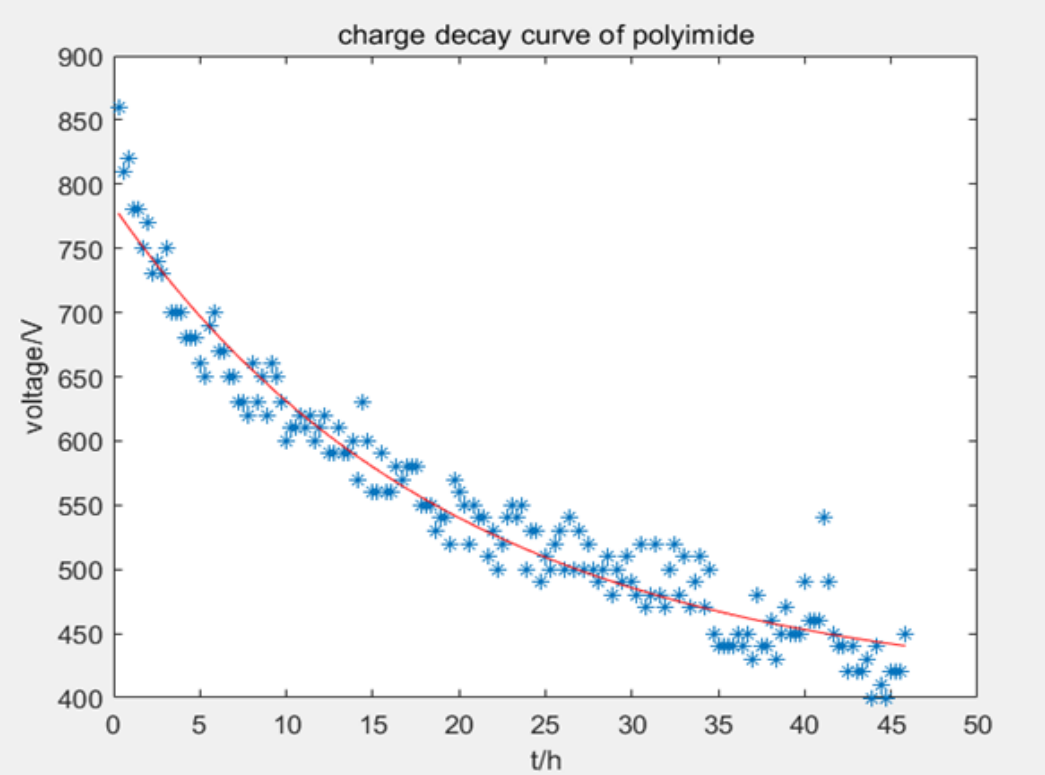


30Mrad irradiation

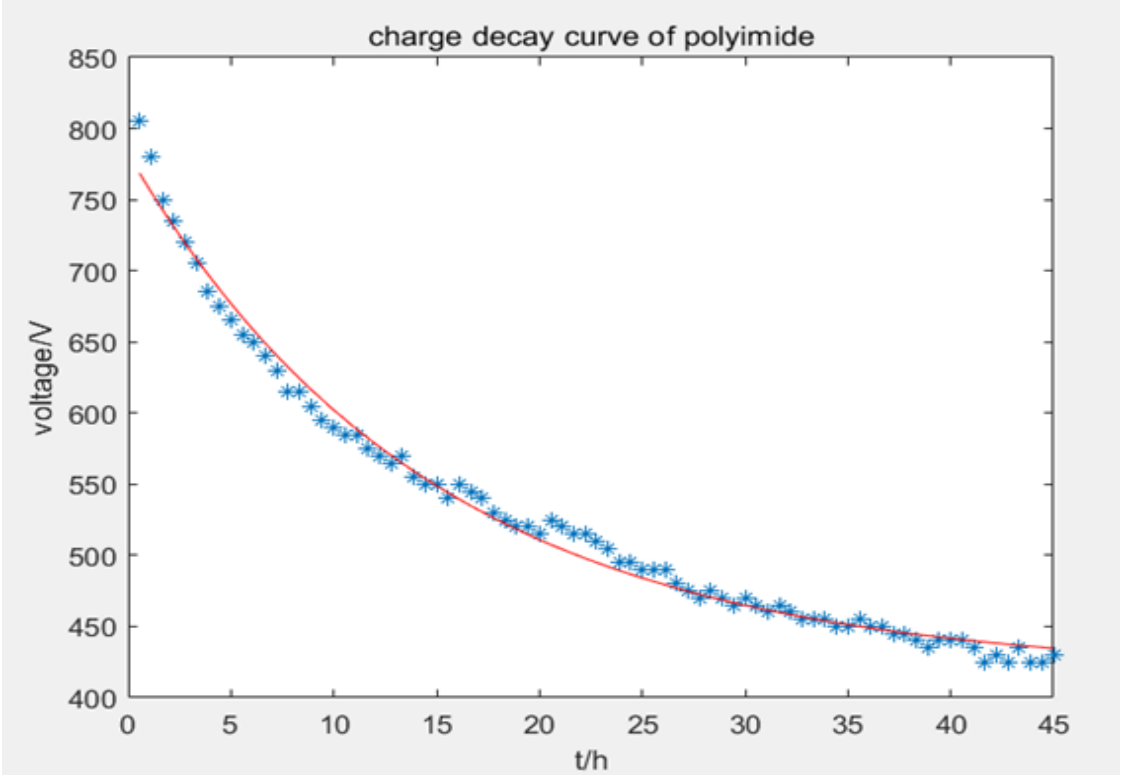
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Results

The result of the ground experiment



After 10Mrad irradiation, the time constant τ =19.1h



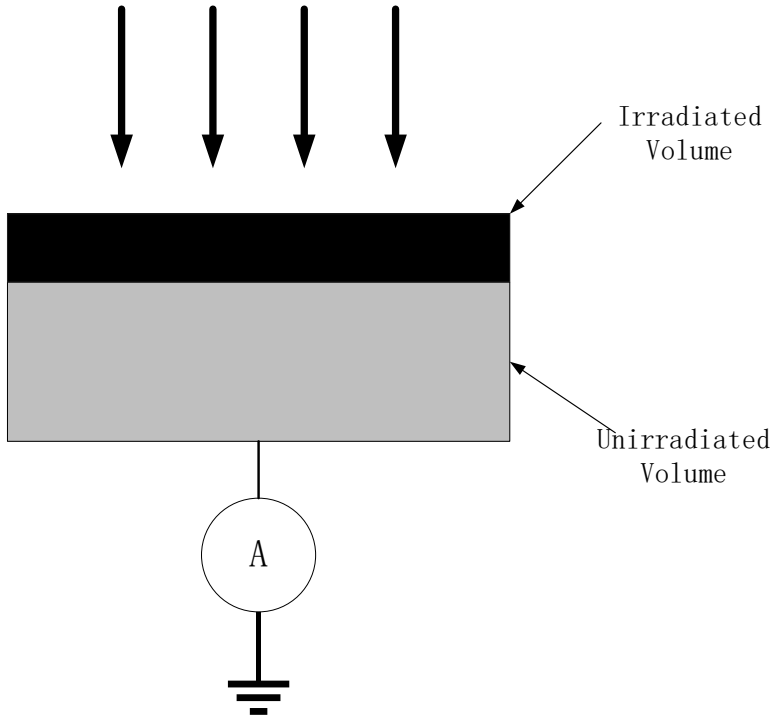
After 30Mrad irradiation, the time constant τ =14.7h

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Results

The result of the ground experiment

Dielectric thickness/um	Radiation dose/Mrad	dielectric constant ε^*	$\frac{1}{\varepsilon^*} - \frac{1}{\varepsilon}$
50	0	1.250	0
50	10	1.207	0.02
50	25	1.129	0.06
50	30	1.093	0.08



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Results

The change of relative permittivity of each layer may be:

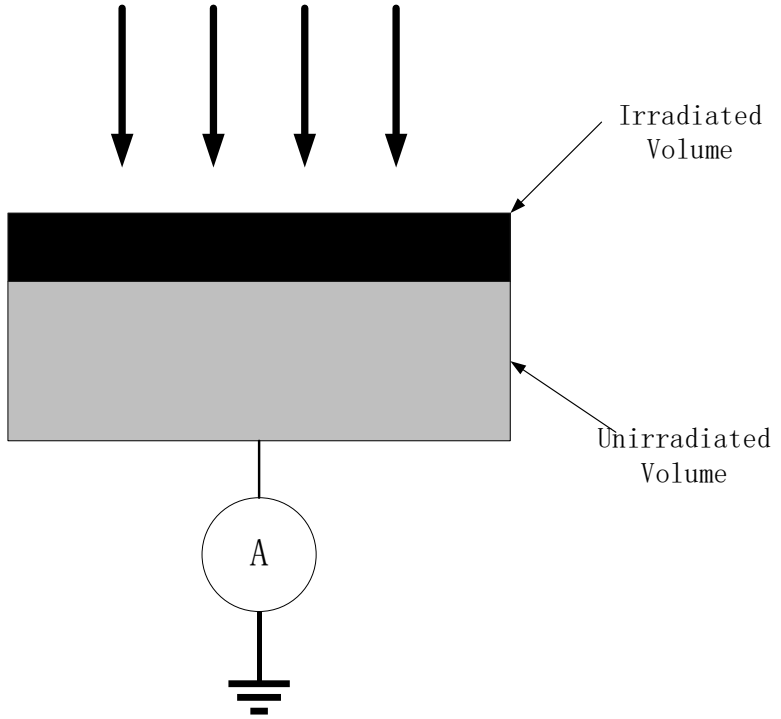
$$\varepsilon_i = \frac{\varepsilon}{1 + kD_i^{\Delta}}$$

The sample can be treated as 50 series capacitor:

$$\frac{d}{\varepsilon_0 \varepsilon^* A} = \sum_{i=1}^{50} \frac{d}{n\varepsilon_0 \varepsilon_i A}$$

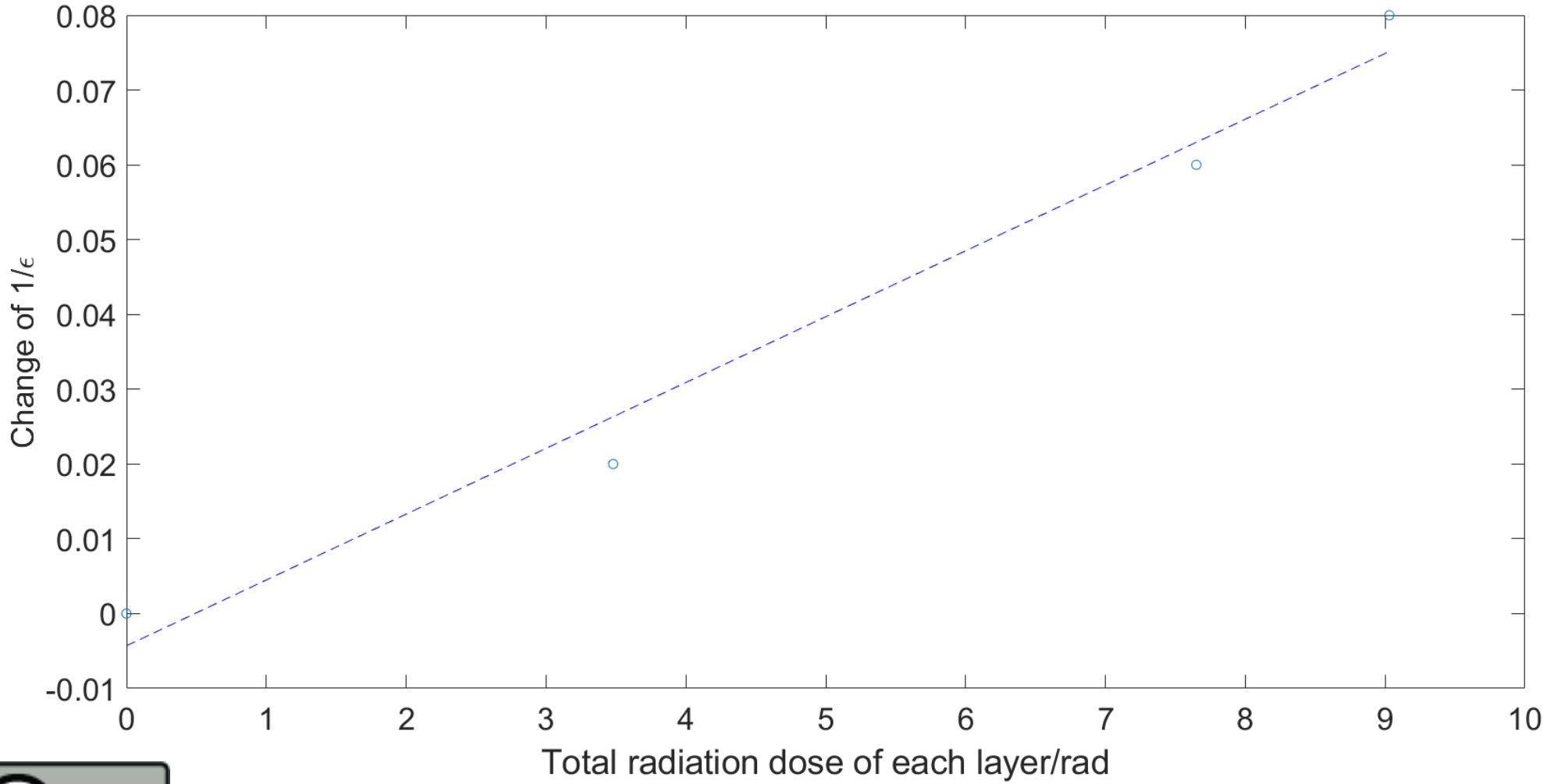
The change of total relative permittivity:

$$\frac{1}{\varepsilon^*} - \frac{1}{\varepsilon} = \frac{k}{n\varepsilon} \sum_{i=1}^{50} D_i^{\Delta}$$



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Results



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1 Introduction

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6 Conclusion

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Conclusion

- The relative permittivity of Polyimide decreased with the increase of total radiation dose.
- The time constant of discharge differs from the total radiation dose received.
- More parameters may be affected by the radiation dose, such as dark conductivity.
- More experiments on different dielectric materials will be carried out when the Covid-19 ends.

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Thanks for listening!

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